Abstracts

PIN Diode Limiter Spike Leakage, Recovery Time, and Damage

R.J. Tan, A.L. Ward, R.V. Garver and H. Brisker. "PIN Diode Limiter Spike Leakage, Recovery Time, and Damage." 1988 MTT-S International Microwave Symposium Digest 88.1 (1988 Vol. I [MWSYM]): 275-278.

A predominantly experimental study was performed on PIN diode-limiter spike leakage, and some preliminary recovery time and damage level results are discussed. Dependencies on the thickness of the intrinsic region (0.5 to 10 µm) and input power at X-band are given.

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